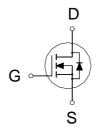
N-Channel Logic Level Enhancement Mode Field Effect Transistor

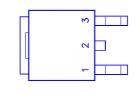
P75N02LDG TO-252 (DPAK)

Lead-Free

PRODUCT SUMMARY

$V_{(BR)DSS}$	R _{DS(ON)}	I _D
25	5m	75A





1. GATE

2. DRAIN

3. SOURCE

ABSOLUTE MAXIMUM RATINGS (T_C = 25 °C Unless Otherwise Noted)

PARAMETERS/TEST C	SYMBOL	LIMITS	UNITS	
Gate-Source Voltage	V_{GS}	±20	V	
Continuous Drain Current	T _C = 25 °C	,	75	
	T _C = 100 °C	- I _D -	50	
Pulsed Drain Current ¹	I _{DM}	170	A	
Avalanche Current		I _{AR}	60	
Avalanche Energy	L = 0.1mH	E _{AS}	140	m.l
Repetitive Avalanche Energy ²	L = 0.05mH	E _{AR}	5.6	mJ
Power Dissipation	T _C = 25 °C	Б	60	W
	T _C = 100 °C	$ P_D$ $-$	32.75	VV
Operating Junction & Storage Temperature	T_{j},T_{stg}	-55 to 150	°C	
Lead Temperature (1/16" from case for	T _L	275		

THERMAL RESISTANCE RATINGS

THERMAL RESISTANCE	SYMBOL	TYPICAL	MAXIMUM	UNITS
Junction-to-Case	$R_{ heta JC}$		2.3	
Junction-to-Ambient	$R_{ heta JA}$		62.5	°C / W
Case-to-Heatsink	$R_{ heta CS}$	0.6		

¹Pulse width limited by maximum junction temperature.

ELECTRICAL CHARACTERISTICS (T_C = 25 °C, Unless Otherwise Noted)

PARAMETER	SYMBOL	TEST CONDITIONS		LIMITS		
FARAMETER	STWBOL	TEST CONDITIONS	MIN	TYP	MAX	UNIT
		STATIC	_	_		_
Drain-Source Breakdown Voltage	$V_{(BR)DSS}$	$V_{GS} = 0V, I_D = 250 \mu A$	25			V
Gate Threshold Voltage	$V_{GS(th)}$	$V_{DS} = V_{GS}, I_D = 250 \mu A$	1	1.5	3	V
Gate-Body Leakage	I _{GSS}	$V_{DS} = 0V$, $V_{GS} = \pm 20V$			±250	nA
Zero Gate Voltage Drain Current	I _{DSS}	$V_{DS} = 20V$, $V_{GS} = 0V$			25	^
Zelo Gale Vollage Dialii Current		$V_{DS} = 20V, V_{GS} = 0V, T_{J} = 125 ^{\circ}C$			250	μΑ

²Duty cycle ≤ 1%

NIKO-SEM

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On-State Drain Current ¹	I _{D(ON)}	$V_{DS} = 10V, V_{GS} = 10V$	70			Α
Drain-Source On-State	D	$V_{GS} = 10V, I_D = 30A$		5	7	m
Resistance ¹	$R_{DS(ON)}$	$V_{GS} = 7V$, $I_D = 24A$		6	8	m
Forward Transconductance ¹	g _{fs}	$V_{DS} = 15V, I_{D} = 30A$		16		S
		DYNAMIC				
Input Capacitance	C _{iss}			5000		
Output Capacitance	C _{oss}	$V_{GS} = 0V, V_{DS} = 15V, f = 1MHz$		1800		pF
Reverse Transfer Capacitance	C_{rss}			800		
Total Gate Charge ²	Q_g			140		
Gate-Source Charge ²	Q_{gs}	$V_{DS} = 0.5V_{(BR)DSS}, V_{GS} = 10V,$		40		nC
Gate-Drain Charge ²	Q_{gd}	$I_D = 35A$		75		
Turn-On Delay Time ²	t _{d(on)}			7		
Rise Time ²	t _r	$V_{DS} = 15V, R_{L} = 1$		7		nS
Turn-Off Delay Time ²	t _{d(off)}	$I_D \cong 30A, V_{GS} = 10V, R_{GS} = 2.5$		24		
Fall Time ²	t _f			6		
SOURCE-DRAIN	DIODE RAT	INGS AND CHARACTERISTICS (T _C	= 25 °	C)		_
Continuous Current	Is				75	^
Pulsed Current ³	I _{SM}				170	Α
Forward Voltage ¹	V _{SD}	$I_F = I_S$, $V_{GS} = 0V$			1.3	V
Reverse Recovery Time	t _{rr}			37		nS
Peak Reverse Recovery Current	I _{RM(REC)}	$I_F = I_S$, $dI_F/dt = 100A / \mu S$		200		Α
Reverse Recovery Charge	Q _{rr}			0.043		μС

 $^{^{1}}$ Pulse test : Pulse Width ≤ 300 μsec, Duty Cycle ≤ 2%.

REMARK: THE PRODUCT MARKED WITH "P75N02LDG", DATE CODE or LOT

Orders for parts with Lead-Free plating can be placed using the PXXXXXXXG parts name.

²Independent of operating temperature. ³Pulse width limited by maximum junction temperature.

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TO-252 (DPAK) MECHANICAL DATA

Dimension	mm			Dimension	mm		
	Min.	Тур.	Max.	Dimension	Min.	Тур.	Max.
Α	9.35		10.4	Н	0.89		2.03
В	2.2		2.4	I	6.35		6.80
С	0.45		0.6	J	5.2		5.5
D	0.89		1.5	K	0.6		1
Е	0.45		0.69	L	0.5		0.9
F	0.03		0.23	М	3.96	4.57	5.18
G	5.2		6.2	N			

